

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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*	B	US-5,623,560	04-1997	Nakajima et al.	382/295
*	C	US-6,560,354	05-2003	Maurer et al.	382/131
*	D	US-7,142,700	11-2006	Van Vaals, Johannes Jacobus	382/128
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.